David Albert receives the 2023 EDFAS Lifetime Achievement Award

The EDFAS Lifetime Achievement Award recognizes those who have given their time, knowledge, and abilities toward the advancement of the electronic device failure analysis industry. The 2023 awardee is David Albert, failure analysis engineer, retired, IBM Corp., Hopewell Jct., N.J. His citation reads: “in recognition of dedication and leadership in the sustained development of the nanoprobing fault isolation technique over 42 years, and being a patient teacher and loyal custodian in EDFAS.”

Dave Albert retired in 2021 after forty-two years with IBM. During most of his career he performed Failure Analysis on electronic devices. These ranged from vendor components IBM purchased (discrete transistors, optoelectronics, microprocessors, etc.), to IBM’s Analytical Service Group for outside customers (optoelectronics and cable TV industry components), to IBM’s Development / Manufacturing Fab (parametric and defectivity test sites covering first Cu metallization and first Silicon-on-Insulator processors, plus memory and logic functional arrays), to IBM’s Processor Product Support (Yield, Burn-In, Reliability Stress, and Card / System / Field Returns). While supporting IBM’s 300mm Wafer Fab, Dave was the Technical Lead within the electrical characterization (yield) group covering FEOL, MOL and Devices.

Dave holds degrees in Electronics and Physics. Over his career he has been involved with optical fault isolation, microprobing, SEM imaging and materials analysis, plus nanoprobing. These evolved into turning functional test and optical fault isolation results into EFA gameplans, plus interpreting nanoprobed transistor data. Twice Dave has taught both Semiconductor Physics and Semiconductor Processing within IBM’s failure analysis and materials analysis area. Also, he has been the Capital Equipment coordinator for his department and his second level manager.

Dave has participated in ISTFA and other conferences over the years. He has authored four ISTFA papers, and been co-author on another five ISTFA papers. Dave is currently a Tutorial presenter and has been a User Group presenter. He serves on ISTFA’s Nanoprobing Committee where he is currently the Chair. Dave has also participated in ASM’s IMAT conference where he teaches his ISTFA Tutorial. Last year Dave taught Microelectronic Failure Analysis as a one-day class within a Failure Analysis course at Ohio State University.

Outside of work, and in retirement, Dave enjoys traveling, hiking, photography, Gravely tractors, and being a missionary.